## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10659593	LEE, BAEK-WOON	
Examiner	Art Unit	
Sherman, Stephen G	2629	

SEARCHED						
Class	Subclass	Date	Examiner			
345	88,600,603-605,613,87-102	11/29/2006	SS			
349	56,82,84,109,143					

SEARCH NOTES					
Search Notes	Date	Examiner			
See attached search history					
Search Updated	11/29/2006	SS			

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			

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